

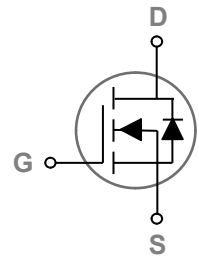
Features

- Die in 8" Wafer Form
- 40V , N-Channel , NGD
- $R_{DS(ON)}=2.5m\Omega$ (Max.) @ $V_{GS}=10V$

Die Description

Applications

- Networking
- LED Lighting Applications
- Quick Charger Applications
- DC-DC Power Management



Parameter	Parameter	Rating	CHIP DRAWING
Die Size (with SL)	2090 X 3060	um ²	
Gate Pad Size	650 X 650		
Source Pad Size	Full Metalized Source Region		
Scribe Line Size	60	um	
Wafer size	200	mm	
Wafer Thickness	4 (±0.4)	mil	
Top Metallization	4um , Al-Cu		
Back Metallization	Ti/Ni/Ag , 1/3/10KÅ		
Gate Bond Wire	5 mil Al x 1		
Source Bond Wire	60 mil Al Ribbon stitch x 1		
Estimated Gross Die	4,550		

Absolute Maximum Ratings $T_c=25^\circ\text{C}$ unless otherwise noted

Symbol	Parameter	Rating	Unit
V_{DSS}	Drain-Source Voltage	40V	V
V_{GSS}	Gate-Source Voltage	+20V / -12V	V
T_J	Operating Junction Temperature Range	-50 to 150°C	°C
T_{STG}	Storage Temperature Range	-50 to 150°C	°C

Electrical Characteristics ($T_J=25^\circ\text{C}$, unless otherwise noted)

Symbol	Parameter	Conditions	Min.	Typ.	Max.	Unit
BV_{DSS}	Drain-Source Breakdown Voltage	$V_{GS}=0V$, $I_D=250\mu A$	40	---	---	V
I_{DSS}	Drain-Source Leakage Current	$V_{DS}=40V$, $V_{GS}=0V$, $T_J=25^\circ\text{C}$	---	---	1	μA
		$V_{DS}=32V$, $V_{GS}=0V$, $T_J=85^\circ\text{C}$	---	---	10	μA
I_{GSS}	Gate-Source Leakage Current	$V_{GS}=20V / -12V$, $V_{DS}=0V$	---	---	±100	nA
$R_{DS(ON)}$	Static Drain-Source On-Resistance	$V_{GS}=10V$, $I_D=20A$	---	2.05	2.5	$m\Omega$
$V_{GS(th)}$	Gate Threshold Voltage	$V_{GS}=V_{DS}$, $I_D=250\mu A$	2	2.8	4	V

Note : 1. The data tested by pulsed , pulse width $\leq 300\mu s$, duty cycle $\leq 2\%$.
 2. $R_{DS(ON)}$ calculated by PPAK5X6 Package